

Electron Beam Lithography @NanoMicroFab: a powerful tool for research and industrial applications







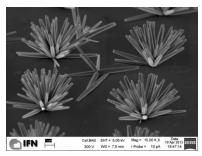
Annamaria Gerardino (CNR IFN Roma)

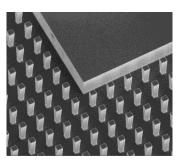




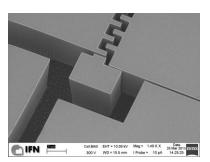
E-beam lithography is a tool for **microelectronics**, **photonics** and **nanotechnology** in general:

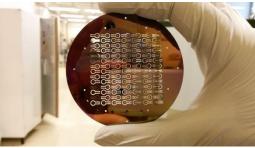
- •Direct writing for <u>advanced prototyping</u> of integrated circuits (photonics on GaAs and Si, waveguides, T-gates, etc.)
- •Research into the <u>scaling limits of integrated circui</u>ts and studies on <u>quantum effects</u> and other novel physics at very small dimensions (single electron transistor, quantum wires, finFET, single photon sources, qubits, etc)
- •Mask-making, typically chrome-on-glass masks for optical lithography

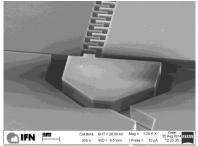


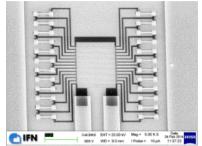








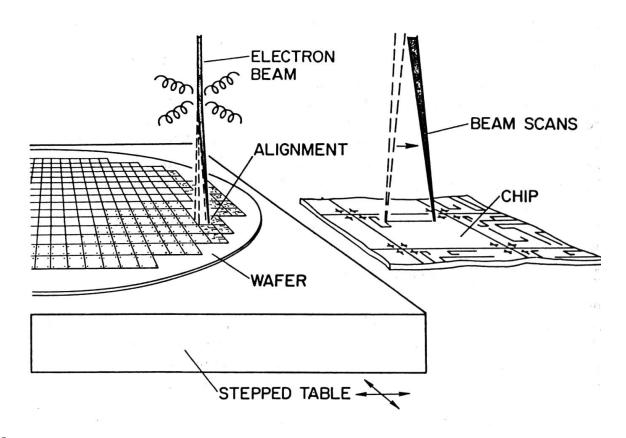








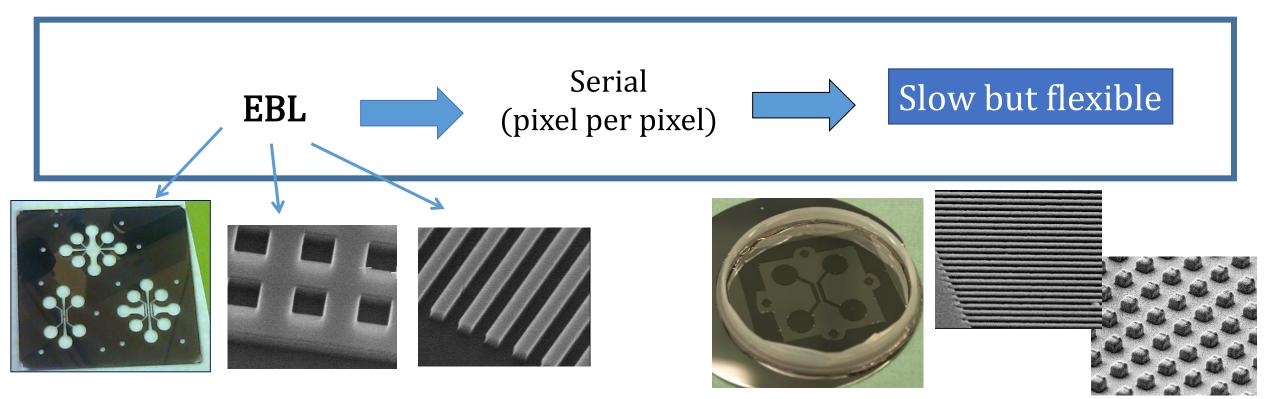
- The e-beam is directed onto a substrate coated with an electronic resist
- The e-beam is deflected to direct write the chosen pattern
- The main deflection is linked to the acceleration voltage and defines writing field of fixed area



■To write on bigger areas, the stage moves; this movement is controlled by laser interferometer (resolution some nms)

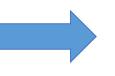








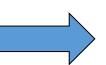
Nanoimprint



parallel

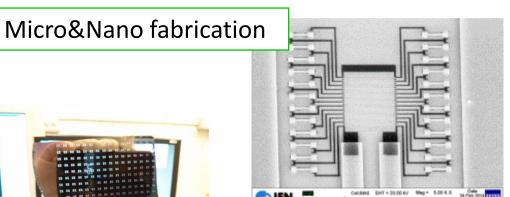
Needs MASKs

Needs template

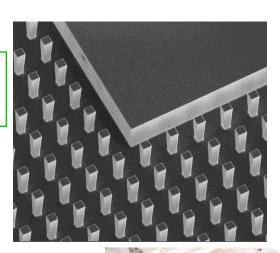


High Throughput but fixed pattern





Thin film & micromachining



Long time know-how

High flexibility in processes and procedures

Single devices & large area processing





The first e-beam lithography machines, based on scanning electron microscope (SEM), were developed in the late 1960s. Shortly thereafter came the discovery that the common PMMA (polymethyl methacrylate) made an excellent electron beam resist.



1985 IESS (Istitute of Solid State Electronics)
LEICA Electron Beam Mask Fabricator
EBMF-10 First e-beam system installed in Italy in

a research center.

LaB6 source

50kV (20kV upgraded)

beam 50nm

PDP 11 computer control

Dismissed in 2004





Raith-Vistec EBPG 5HR Installed in 2004 @CNR IFN



- field emission gun FEG
- 100kV
- beam diameter: 8 nm
- 10 MHz frequency
- block size 560µm
- laser interferometer ($\lambda/120 \sim 5$ nm)
- Hight sensor
- overlay accuracy <20nm
- direct writing (up to 4")
- mask fabrication (up to 4")
- current: 0,1-100nA





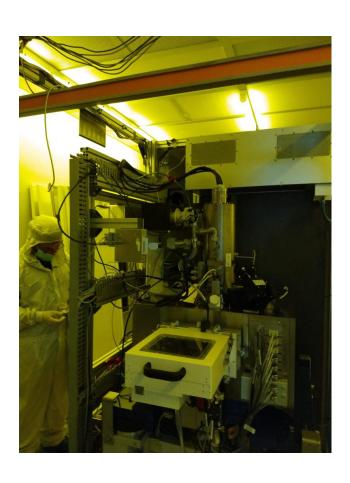
RAITH VOYAGER installed in July 2020 @NanoMicroFab

- •50 kV FEG
- Step frequency max. 50 MHz
- Minimum linewidth: <8 nm
- Mask fabrication up to 6"
- direct writing up to 6"
- Sample loading up to 8"



INSTALLATION









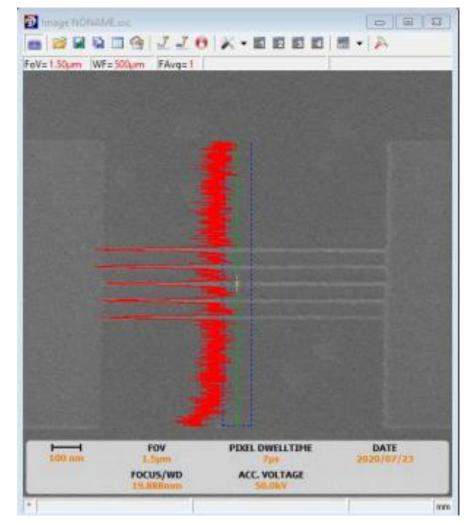


QUALIFICATION TEST

Image NONAME as O B 83 FoV=1.50um WF=500um FAvg=1 FOV. PEKEL DWELLTIME DATE ACC. VOLTAGE FOCUS/WD THU-0.000618 V-0.000750 U=0.022281

High resolution result imaged in the VOYAGER at 50kV. PITCH: 35 nm; line: 15 nm

Result of the smallest linewidth test imaged in the VOYAGER at 50kV.







Quantum/ photonics

Detectors

Sensors

RESOLUTION DOWN TO FEW NM

PROTOTYPING; MIX AND MATCH PROCESSES; HIGH POSITIONING PRECISION; FLEXIBILITY

Bio

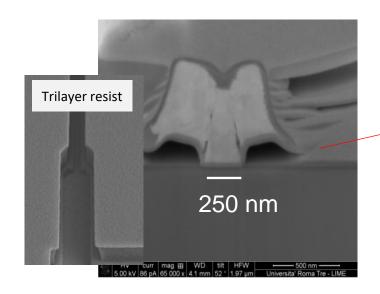
LAB ON CHIP; POINT OF CARE; MICROFLUIDICS

User oriented

Technology Transfer



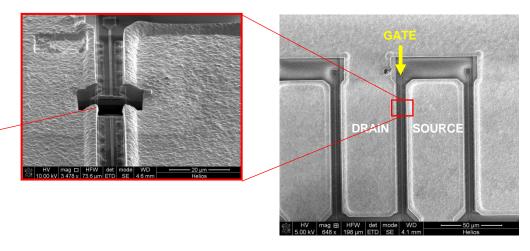




T-gate with Lg = 250nm

Single e-beam writing

- Trilayer PMMA/COP33/COP8
- EBL
- Development and metallization

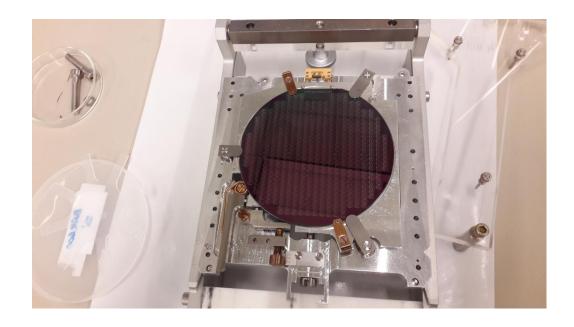


HEMT high power amplifiers and/or low noise amplifier for radar applications

- Collaboration with Leonardo Company
- Technology transfer
- EBL used as SLX standard process in field-plate technology Lg=250nm



- EBPG 5200ES is now in production line
- Totally dedicated to production
- R&D is developed @IFN CNR





THANK YOU FOR ATTENTION!

annamaria.gerardino@cnr.it

